

<b>Notice of References Cited</b>	Application/Control No. 10/532,826		Applicant(s)/Patent Under Reexamination KATAYAMA ET AL.	
	Examiner William C. Doerrler		Art Unit 3744	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2,899,381	08-1959	Jonkers	62/6
*	B	US-2,958,935	11-1960	TEUNIS BLOEM ALDERT	29/890.034
*	C	US-3,445,910	05-1969	DURYEE HARRY I; et. al.	29/890.034
*	D	US-5,429,177	07-1995	Yaron et al.	165/10
*	E	US-5,746,269	05-1998	Torii et al.	165/10
*	F	US-6,456,898	09-2002	Modesto et al.	700/206
*	G	US-6,474,075	11-2002	Tanaka et al.	62/6
*	H	US-6,544,628	04-2003	Aull et al.	428/179
*	I	US-6,640,427	11-2003	Aull et al.	29/796
*	J	US-6,745,822	06-2004	Mitchell, Matthew P.	165/10
*	K	US-2005/0011632	01-2005	Tanaka et al.	165/004
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.